

REMARKS

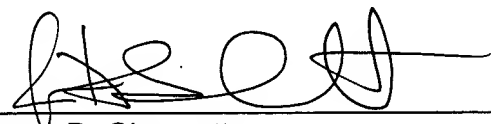
Claims 31-42, 54-65, 67-70, and 75-88 were indicated to be allowable in the parent application. This request for continued examination is being submitted out of an overabundance of caution to have the allowed claims considered in light of art which was recently discovered by Applicants. Such art is cited in an accompanying Information Disclosure Statement.

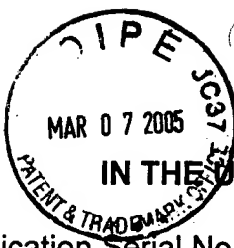
Applicants also submit herewith a copy of an Information Disclosure Statement and form PTO-1449 filed December 13, 2004. Applicants request return of the initialed form PTO-1449 to Applicants.

The Examiner is requested to phone the undersigned if the Examiner believes such would facilitate prosecution of the present application. The undersigned is available for telephone consultation at any time during normal business hours (Pacific Time Zone).

Respectfully submitted,

Dated: 3/7/05

By: 
James D. Shaurette
Reg. No. 39,833



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/844,175
Filing Date April 27, 2001
Inventorship Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Group Art Unit 2858
Examiner R. Kobert
Attorney's Docket No. MI22-1703
Title: Removable Electrical Interconnect Apparatuses and Removable Engagement
Probes

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

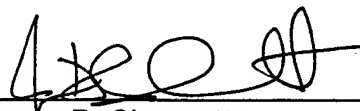
References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No
admission is made regarding whether all the submitted references are prior art.

EV372471170

Respectfully submitted,

Dated: 12/10/04

Attorney: 
James D. Shaurette
Reg. No.: 39,833

Form PTO-1449

MAR 07 2005

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1703SERIAL NO.
09/844,175

LIST OF ARTS CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT
Warren M. Farnworth et al.FILING DATE
April 27, 2001GROUP
2858

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,585,282	12/17/1996	Wood et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.